

L Number	Hits	Search Text	DB	Time stamp
1	26	halton adj sequence\$1	USPAT; US-PGPUB	2004/07/08 15:46
2	20	(halton adj sequence\$1) and scan\$4	USPAT; US-PGPUB	2004/07/08 15:55
3	877	((low discrepancy) or Halton or Sobol or Faure or Niederreiter) adj sequence\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 15:56
4	877	((low discrepancy) or Halton or Sobol or Faure or Niederreiter) adj sequence\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 16:02
5	32	((low discrepancy) or Halton or Sobol or Faure or Niederreiter) adj sequence\$1) same (scan\$1 or scanning or scanned)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 16:02
6	22	((low discrepancy) or Halton or Sobol or Faure or Niederreiter) adj sequence\$1) same (scan\$1 or scanning or scanned)) not ((halton adj sequence\$1) and scan\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 15:59
7	81	((low adj discrepancy) or Halton or Sobol or Faure or Niederreiter) adj sequence\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 16:02
8	14	((low adj discrepancy) or Halton or Sobol or Faure or Niederreiter) adj sequence\$1) same (scan\$1 or scanning or scanned)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 16:02
9	4	((low adj discrepancy) or Halton or Sobol or Faure or Niederreiter) adj sequence\$1) same (scan\$1 or scanning or scanned)) not ((halton adj sequence\$1) and scan\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 16:03
-	78	low adj discrepancy adj (curve\$1 or curve\$1 or point\$1 or sequence\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 16:46
-	78	low adj discrepancy adj (curve\$1 or scan\$4 or point\$1 or sequence\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 16:46
-	82	low adj discrepancy adj2 (curve\$1 or scan\$4 or point\$1 or sequence\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 17:10
-	260	(low adj discrepancy) or Hammersley	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 17:12
-	17	((low adj discrepancy) or Hammersley) with scan\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 17:12
-	1	((low adj discrepancy) or Hammersley) with scan\$4) not (low adj discrepancy adj2 (curve\$1 or scan\$4 or point\$1 or sequence\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 17:12

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TI DIMENSIONAL MEASUREMENT OF SURFACES AND THEIR SAMPLING
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CS UNIV MICHIGAN, DEPT IND & OPERAT ENGN, 1205 BEAL AVE, ANN ARBOR, MI, 48109
(Reprint)
CYA USA
SO COMPUTER-AIDED DESIGN, (APR 1993) Vol. 25, No. 4, pp. 233-239.
ISSN: 0010-4485.
DT Article; Journal
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REC Reference Count: 33
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AN 93:244079 SCISEARCH
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TI DIMENSIONAL MEASUREMENT OF SURFACES AND THEIR SAMPLING
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ISSN: 0010-4485.
DT Article; Journal
FS ENGI
LA ENGLISH
REC Reference Count: 33
AB The number of the discrete samples for the dimensional measurement of
machined surfaces and their coordinates is investigated. Counter to
intuition, there need not be quadratically more samples than in the case
for sampling lines or curves. To justify this novel scheme, accuracy is
defined as the discrepancy of a finite point set. Then, from number
theory, a particular sequence of numbers is used to compute the sampling
coordinates, resulting in a number that is linear in 1D, at the same level
of accuracy that is achieved by a 2D uniform distribution. Finally,
experimental results of the measurement of machined surfaces modeled as
random processes are compiled.
CC COMPUTER SCIENCES, SPECIAL TOPICS; COMPUTER SCIENCE, SOFTWARE, GRAPHICS,
PROGRAMMING
ST Author Keywords: COORDINATE MEASUREMENT; OPTICAL SCANNING;
SURFACE ROUGHNESS; LOW-DISCREPANCY POINT SETS
RF 92-3302 001; THERMAL CONTACT RESISTANCE; ROCK FRICTION; FRACTAL

INHOMOGENEITY; ROUGH SURFACES; FAULT SYSTEMS; CAJON PASS DRILL HOLE;
 LUBRICANT FILM MODELING
 92-6915 001; STOCHASTIC MAJORIZATION; OPTIMAL STATIONARY POLICIES; GI/G/1
 QUEUE; GENERALIZED SEMI-MARKOV PROCESSES; TRANSACTIONAL DATA; REAL-TIME
 SYSTEMS

RE

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	1982			ISO R1101 INT STAND
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Relevance scale ☐ ☐ ☐ ☐ ☐**1 Induced well-distributed sets in Riemannian spaces**

Lothar Wenzel, Ram Rajagopal, Dinesh Nair

March 2003 **ACM Transactions on Mathematical Software (TOMS)**, Volume 29 Issue 1Full text available: pdf(389.61 KB) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

The concept of Riemannian geometries is used to construct induced homogeneous point sets on manifolds that are based on well-distributed point sets in unit cubes of an appropriately chosen Euclidean space. These well-distributed point sets in unit cubes are based on standard low-discrepancy sequences. The approach is algorithmic, that is, the methods developed in this article have been implemented and tested. Applications in image processing, graph theory and measurement-based exploration are pr ...

Keywords: Riemannian geometry, image processing, low-discrepancy sequences, well-distributed point sets

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Relevance scale ☐ ☐ ☐ ☐ ☐**1** [Algorithm 806: SPRNG: a scalable library for pseudorandom number generation](#)

Michael Mascagni, Ashok Srinivasan

September 2000 **ACM Transactions on Mathematical Software (TOMS)**, Volume 26 Issue 3Full text available: [pdf\(158.69 KB\)](#) Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

In this article we present background, rationale, and a description of the Scalable Parallel Random Number Generators (SPRNG) library. We begin by presenting some methods for parallel pseudorandom number generation. We will focus on methods based on parameterization, meaning that we will not consider splitting methods such as the leap-frog or blocking methods. We describe, in detail, parameterized versions of the following pseudorandom number generators: (i) linear congruential generators, ...

Keywords: lagged-Fibonacci generator, linear congruential generator, parallel random-number generators, random-number software, random-number tests

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